



Session Title: [TuA1] Phosphides
Session Date: July 14 (Tue.), 2026
Session Time: 08:30-10:15
Session Room: Room A (Baekrok Hall B-1, 1F)
Session Chairs

[TuA1-1] [Invited] 08:30-09:00

Growth Management of InP-Based Optoelectronic and Microelectronic Devices on InP-on-Silicon (InPoSi) Wafers

C. Besancon¹, D. Néel¹, N. Vaissière¹, E. Izquierdo¹, A. Elias¹, G. Daccord¹, J.L. Reverchon¹, O. Delorme¹, A. Wilk¹, N. Davy¹, V. Nodjiadjim¹, C. Mismar¹, F. Fortunato², J. Bergsten³, H. Rodilla², B. Ghyselen⁴, L. Sanchez⁵, T. Bria⁵, F. Fournel⁵, and J. Decobert¹, ¹ III-V Lab, France, ² Chalmers University of Technology, Sweden, ³ Low Noise Factory, Sweden, ⁴ SOITEC, France, ⁵ CEA-Leti, France

[TuA1-2] 09:00-09:15

Impact of Growth Parameters on High Quality InP Microridges Grown Directly on On-Axis Si Substrates

T. Meyer¹, A. Baechle¹, M. Prescher¹, L. Kirste¹, R. Keil¹, M. Haertelt¹, P. Merkert¹, S. Messaoudène², L. Andreutti², M. Doron², B. Ben Bakir², A. Trampert², and R. Aidam¹, ¹ Fraunhofer IAF, Germany, ² CEA-Leti, France, ³ Paul-Drude-Institut für Festkörperelektronik, Germany

[TuA1-3] 09:15-09:30

Orientation Patterned Gallium Phosphide for Integrated Nonlinear Photonics

B. Le Corre^{1,2}, S. Combré², M. Millotte¹, G. Beaudoin¹, A. Harouri¹, L. Le Gratiet¹, I. Sagnes¹, B. Gérard⁴, A. De Rossi³, A. Grisard³, G. Patriarche¹, Y. Léger², and K. Pantzas¹, ¹ Université Paris-Saclay, France, ² Université de Rennes, France, ³ Thales Research and Technology, France, ⁴ III-V Lab, France

[TuA1-4] 09:30-09:45

Optimized GaP Nucleation on Silicon for III-V Multi-Junction Solar Cell Integration

J. Ohlmann¹, J. Grutke^{1,2}, A. Beyer³, D. Lackner¹, K. Volz², T. Hannappel⁴, A.W. Bett^{1,2}, and F. Dimroth¹, ¹ Fraunhofer Institute for Solar Energy Systems ISE, Germany, ² University of Freiburg, Germany, ³ University of Marburg, Germany, ⁴ TU Ilmenau, Germany

[TuA1-5] 09:45-10:00

Resistive Ru-Doped InP Layers for Improved Semi-Insulating Buried Heterostructures

Gustavo Afonso, Nicolas Vaissiere, Antoine Elias, Cosimo Calo, Vladyslav Vakarin, Giancarlo Cerulo, Mokhtar Kortí, Olivier Parillaud, Frederic Pommereau, and Jean Decobert, III-V Lab, France

[TuA1-6] 10:00-10:15

In-Situ Reflectometry and Curvature Monitoring for Process Control of InP-Based Laser Heterostructures Grown by MOVPE

K. Haberland¹, J. Decobert², N. Vaissiere², V. Bot², C. Besancon², and F. Weigert¹, ¹ LayTec AG, Germany, ² III-V Lab, France